Green Journals

International Approved Journals

Journal Information

Journal Title	Russian Microelectronics
Publisher	Pleiades Publishing
ISSN	1063-7397
E-ISSN	1608-3415
Database	SCOPUS
Domain	Physical Sciences

Classification History

Year	A+	A	B	C
2026			✓	
2025			✓	
2024			✓	
2023			✓	
2021/2022			✓	
2020			✓	
2019			✓	
2018				

Classification: The table above shows all journal classifications recorded for each classification year in the Green Journals database. A journal may have more than one classification in the same year.

Recent Articles

Design of High-Performance Low-Power Adder Circuits, 2 to 4 Decoder and 2 × 1 Mux Using RLG for VLSI Applications
2026-4 Vol. 55 Issue 2 Pages 369-375
Authors: Syed Zahiruddin, P. Subbarayudu, P. V. S. Murali Krishna et al.
DOI: 10.1134/s1063739726600056

Dephasing of a Charge Qubit in a Stochastic Field of Oscillating Electrons
2026-4 Vol. 55 Issue 2 Pages 258-268
Authors: N. V. Kulagin, A. V. Tsukanov
DOI: 10.1134/s1063739726600317

Optimization of Wireless Data Transmission in Three-Dimensional Integrated Circuits Using Nanophotonic Devices: Challenges and Solutions
2026-4 Vol. 55 Issue 2 Pages 332-339
Authors: D. A. Serov, I. A. Khorin
DOI: 10.1134/s1063739725602310

Electroplasticity of Metallic Nanowires for Ultrashort Current Loads
2026-4 Vol. 55 Issue 2 Pages 252-257
Authors: S. Sh. Rekhviashvili
DOI: 10.1134/s1063739726600287

DFT Modeling of Nitrogen Adsorption and Doping in A15-Type Intermetallic Ti3Sb
2026-4 Vol. 55 Issue 2 Pages 239-251
Authors: M. M. Asadov, S. O. Mammadova, S. N. Mustafaeva et al.
DOI: 10.1134/s1063739726600603

Design and Optimization of CMOS Two-Stage Operational Amplifier Using Hippopotamus Optimization Algorithm
2026-4 Vol. 55 Issue 2 Pages 396-404
Authors: Suvashish Kund, Bishnu Prasad De, Sandeep Kumar Dash et al.
DOI: 10.1134/s1063739725601092

Compact Model for Uniaxial Strain-Induced Threshold Voltage Shift in High-k/Metal Gate Nanoscale Bulk MOSFETs
2026-4 Vol. 55 Issue 2 Pages 376-385
Authors: Yashu Swami
DOI: 10.1134/s1063739726600044

Estimating the Stochastic Reliability of a KP961 Power Transistor under Thermal Cycling Using the Monte Carlo Simulation
2026-4 Vol. 55 Issue 2 Pages 289-303
Authors: T. I. Isabekova, A. R. Shakhmaeva
DOI: 10.1134/s1063739726600305

Modeling the Temperature Dependence of Photoconductivity of Sensitized Indium Phosphide with a Deep Copper Impurity
2026-4 Vol. 55 Issue 2 Pages 269-279
Authors: Ph. V. Makarenko, K. V. Zol’nikov, A. V. Achkasov et al.
DOI: 10.1134/s1063739726600354

FinFET-Based SRAM Cell Using Low-Power Technique for Leakage and Stability Optimization
2026-4 Vol. 55 Issue 2 Pages 386-395
Authors: Ekta Jolly, Vijay Kumar Sharma, Anil Kumar Bhardwaj
DOI: 10.1134/s1063739725602334